Elastic Moduli of (Ni,Cu)₃Sn₄ Ternary Alloys from First-Principles Calculations

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Based on first-principles calculations, the effect of Cu solubility on the elastic moduli of Ni₃Sn₄-based intermetallic compound (IMC) is investigated. It is found that the stiffness tensor of a (Ni,Cu)₃Sn₄ single crystal is anisotropic, and the presence of Cu in the crystal compound reduces the moduli of (Ni,Cu)₃Sn₄ due to reduced hybridization between Ni and Sn states. Furthermore, our results show that higher Cu concentration in the (Ni,Cu)₃Sn₄-based IMCs leads to thermodynamically less stable compounds. Based on the single-crystal results, the elastic properties of polycrystalline (Ni,Cu)₃Sn₄ are also obtained.

Key words: Lead-free solder, intermetallic compound, first principles, density of states, single crystal, elastic property

INTRODUCTION

Ni-based finishes, e.g., electroless nickel immersion gold (ENIG), are widely used in electronic packaging. The Ni₃Sn₄ intermetallic compound (IMC) is often found at the interface between Snbased lead-free solders and ENIG.1-4 The thermomechanical behavior of such IMCs often plays an important role in determining the failure of solder/ pad interfaces; for example, it is well known that excessive IMC growth at the interface can compromise the reliability of solder joints, because IMCs are typically stiffer and brittle. With the everincreasing demands for miniaturization of electronic devices, the size of solder joints is being reduced dramatically. This reduced solder volume increases the IMC volume fraction of the total volume of the solder joint, making the interfacial behavior more prominent. Recent adoption of leadfree solders further aggravates the influence of interfacial IMCs.

Therefore, it is crucial to know IMCs' thermomechanical properties in order to evaluate solder joint reliability in electronic packaging. One of the most important thermomechanical properties of IMCs is their elastic stiffness. However, existing data on Ni_3Sn_4 elastic constants seem to vary over a wide range; for instance, the reported Young's moduli are between 134 GPa and 158 GPa when measured using nanoindentation, and between 94 GPa and 118 GPa when measured using other methods.⁵⁻⁹

Sn-Ag-Cu ternary lead-free solders have been accepted as some of the best candidates for replacement of conventional Sn-Pb solders in electronic packaging. It has been observed that traces of Cu are often present in the Ni₃Sn₄ IMC, where the Cu atoms substitute for the Ni sublattice. Such Ni₃Sn₄-based IMC is usually labeled (Ni,Cu)₃Sn₄.¹⁻⁴ It is plausible that the presence of Cu may alter the elastic stiffness of this IMC. The focus of the present work is to investigate this effect using a density-functional theory approach. Although, several recent studies have been performed to calculate the elastic properties of binary IMCs that are commonly formed in the solder joint, such as Cu₆Sn₅, Ni₃Sn₄, Ag₃Sn, Cu₃Sn, etc.,¹⁰⁻¹² very few works have studied Ni-Cu-Sn ternary IMCs.

Ni₃Sn₄-BASED MODEL AND SIMULATION METHOD

The Ni₃Sn₄ IMC has a monoclinic crystal structure (space group C2/m).¹³ Figure 1a depicts the crystal structure of Ni₃Sn₄, in which the Ni atoms

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Fig. 1. (a) Unit cell of Ni_3Sn_4 ; the small blue spheres represent the Ni atoms and the large green spheres represent the Sn atoms. (b) The $Ni_1Cu_2Sn_4$ phase, in which the 4i Ni atoms are replaced by Cu atoms.

occupy the 2a and 4i space sites and the Sn atoms are located at two different 4i positions. It has been shown that, in (Ni,Cu)₃Sn₄, the Cu atoms substitute for the Ni sublattice and do not change the basic crystal structure of Ni₃Sn₄.¹ Therefore, in this study, the Ni atoms at the 2a site are replaced by Cu atoms according to the formula Ni₂Cu₁Sn₄, which yields a Cu concentration of 14.3 at.%. Similarly, the formula Ni₁Cu₂Sn₄ represents the crystal structure in which the Cu atoms substitute for Ni atoms at the 4i site, as shown in Fig. 1b, which yields a Cu concentration of 28.6 at.%.

First-principles calculations were performed using CASTEP software.^{14,15} The software uses the plane-wave pseudopotential method and performs energy minimization by the Broyden-Fletcher-Goldfarb-Shanno method. The Perdew-Burke-Ernzerhof (PBE) generalized gradient approximation (GGA) functional was employed to deal with the exchange correlation. The pseudo-atomic calculation was conducted for the following electron configurations: $3d^84s^2$ of Ni, $3d^{10}4s^1$ of Cu, and $5s^25p^2$ of Sn. The original lattice constants used as input for the geometry optimization were a = 12.214 A. b = 4.060 Å, c = 5.219 Å, and $\beta = 105.0^{\circ}.^{13}$ The energy of the Ni₃Sn₄-based crystal structure was minimized with respect to the lattice constants and any interior degree of freedom. Convergence was considered to be achieved when the following

IMCs	Lattice Parameters (Å) by GGA-PBE
Ni_3Sn_4	a = 12.34460, b = 4.11096,
	$c = 5.32335, \beta = 105.495$ experiment : a = 12.2146, b = 4.0602,
	$c = 5.2913, \ \beta = 105.010$
$Ni_2Cu_1Sn_4$	a = 12.42553, b = 4.22212,
(Cu at $2a$ site)	$c = 5.31220, \ \beta = 105.977$
$Ni_1Cu_2Sn_4$	a = 12.55115, b = 4.19994,
(Cu at $4i$ site)	$c = 5.44223, \beta = 106.102$

Table I. *Ab initio* calculated lattice parameters of (Ni,Cu)₃Sn₄ ternary crystals

conditions were met simultaneously: energy change below 5×10^{-6} eV/atom, force less than 0.01 eV/Å, stress less than 0.02 GPa, and displacement change less than 5×10^{-4} Å. The energy cutoff was set as 330 eV, and the *k*-point set was $7 \times 7 \times 5$.

To calculate the elastic constants, the optimized (Ni,Cu)₃Sn₄ unit cell was subjected to deformation with various states of strain, in the same manner as used in Karki et al.¹⁶ Specifically, the nonzero strain components used for the four states of strain were, respectively, (i) ε_{11} and ε_{23} , (ii) ε_{33} and ε_{12} , (iii) ε_{22} , and (iv) ε_{13} . In each strain state, the magnitude of these nonzero strain components was gradually increased from 0 to 0.003. For each strain increment, the energy of the unit cell was minimized with the cell vectors fixed, and the corresponding stresses were obtained. The elastic constants were then extracted from a liner fit with the strain increment. Table I shows the lattice parameters obtained from the ab initio calculations. It can be seen that the lattice parameters for Ni₃Sn₄ calculated using GGA agree very well with the ambienttemperature experimental data.¹³

Comparing with the lattice parameters of the pure Ni_3Sn_4 crystal structure, we found that the presence of Cu increases the volume of the Ni_3Sn_4 base structure. This may be an indication that Cu occupancy in Ni_3Sn_4 reduces the binding inside the Ni_3Sn_4 crystal structure. To study thermodynamic stability, the total energy of the $(Ni,Cu)_3Sn_4$ crystal was first computed. This total energy was then used to calculate the heat of formation to determine the thermodynamic stability. The heat of formation is related to the composition-average energies of the pure component elements in their equilibrium crystal structure.¹⁷ Therefore, for the formula $Ni_mCu_nSn_k$, the heat of formation at zero Kelvin is given by:

$$\Delta E = \frac{1}{m+n+k} \Big[E_{\mathrm{N}i_m\mathrm{Cu}_n\mathrm{Sn}_k}^{\mathrm{total}} - (mE_{\mathrm{N}i} + nE_{\mathrm{Cu}} + kE_{\mathrm{Sn}}) \Big],$$
(1)

where ΔE is the heat of formation, $E_{\text{Ni}_m\text{Cu}_n\text{Sn}_k}^{\text{total}}$ is the total energy of $\text{Ni}_m\text{Cu}_n\text{Sn}_k$, E_{Ni} , and E_{Cu} , and E_{Sn} are the energies of the elements Ni, Cu, and Sn,

Table II.	Heat	of	formation	of	$(Ni,Cu)_3Sn_4$	ternary
crystals						

IMCs	Heat of Formation (eV/atom)
Ni ₃ Sn ₄	-0.316
$Ni_2Cu_1Sn_4$ (Cu at $2a$ site)	-0.237
$Ni_1Cu_2Sn_4$ (Cu at $4i$ site)	-0.180

respectively. In this study, Ni and Cu have the facecentered cubic structure, and Sn is taken as having the β -Sn crystal structure. The computed heat of formation of the different (Ni,Cu)₃Sn₄ phases is presented in Table II. Based on our results, the heat of formation of Ni₃Sn₄ itself is -0.316 eV/atom (about -30.49 kJ/mol). This is comparable to previously reported values of -28.16 kJ/mol (by local density approximation), -23.28 kJ/mol (GGA)¹⁸ -34.26 kJ/mol,¹⁹ and -25.41 kJ/mol²⁰ (by calculation of phase diagram, CALPHAD), as well as the reported experimental results of -29.68 kJ/mol²¹ and -28.76 kJ/mol,²² both at 298 K. This partially validates our implementation of the first-principles calculations.

It is seen from Table II that all the values of heat of formation are negative. However, Ni₃Sn₄ has the highest absolute value (or lowest heat of formation) among the three phases considered, indicating that the Ni₃Sn₄ crystal structure is more thermodynamically stable. Furthermore, Ni₁Cu₂Sn₄ has a higher heat of formation than Ni₂Cu₁Sn₄, indicating that the higher Cu concentration in (Ni,Cu)₃Sn₄ leads to a higher heat of formation. Since the Cu concentration in $Ni_2Cu_1Sn_4$ is 14.3 at.%, it can be concluded that the Cu solubility in the (Ni,Cu)₃Sn₄ phase should not exceed 14.3 at.%. In fact, it has been found that usually the maximum Cu solubility in (Ni,Cu)₃Sn₄ is approximately 7.0 at.% to 8.0 at.%, $^{1-3,23}$ although a (Ni,Cu)₃Sn₄ phase with a slightly higher Cu concentration (10.6 at.%) has also been reported.³

The elastic properties of the three phases, Ni_3Sn_4 , $Ni_2Cu_1Sn_4$, and $Ni_1Cu_2Sn_4$, were all calculated by using the first-principles approach. Figure 2 illustrates the computed stiffness matrix of singlecrystal (Ni,Cu)_3Sn_4. It is seen that, in all three phases, c_{33} is greater than c_{11} and c_{22} , indicating elastic anisotropy. Furthermore, c_{11} , c_{22} , and c_{33} of Ni_3Sn_4 are all greater than those of $Ni_2Cu_1Sn_4$ and $Ni_1Cu_2Sn_4$, indicating a higher binding force in Ni_3Sn_4 than in (Ni,Cu)_3Sn_4. This is consistent with the calculated results of heat of formation, as shown in Table II.

The calculated single-crystal elastic constants in Fig. 2 cannot be validated directly, as there are no experimental results for comparison. To validate the calculated results, corresponding polycrystalline elastic moduli were computed based on the Voight-Reuss-Hill (VRH) approach.²⁴ The results are presented in Table III. It is seen that the results in

[155.0	70.2	66.4	0.0	-21.1	0.0	
	155.7	71.8	0.0	9.9	0.0	
		180.1	0.0	-8.6	0.0	
			57.6	0.0	9.9	
				59.9	55.8	
(a) 55.8						
[136.5	57.6	57.7	0.0	-21.9	0.0]	
	140.5	65.2	0.0	11.6	0.0	
		162.3	0.0	-4.2	0.0	
			51.7	0.0	8.9	
				48.2	0.0	
(b) 47.8						
[128.5	52.9	54.6	0.0	-18.8	0.0]	
	136.2	65.7	0.0	9.0	0.0	
		141.1	0.0	-2.2	0.0	
			41.7	0.0	7.3	
				44.1	0.0	
L		(0	;)		46.4	
Stiffness	matrix	of sin	ale-crv	stal IMC	(a)	NicS

Fig. 2. Stiffness matrix of single-crystal IMCs: (a) Ni_3Sn_4 , (b) $Ni_2Cu_1Sn_4$, and (c) $Ni_1Cu_2Sn_4$.

Table III for Ni_3Sn_4 are consistent with the values measured by nanoindentation.^{5–8} For the $(Ni,Cu)_3Sn_4$ phases, the Young's modulus measured by nanoindentation is 164.9 GPa.²⁵ This is quite different from our calculated result. This difference may be attributed to the thin $(Ni,Cu)_3Sn_4$ layer used for the nanoindentation test. In addition, the lower Cu concentration in $(Ni,Cu)_3Sn_4$ may also be a factor. The results in Table III show that Ni_3Sn_4 has larger elastic moduli than those of $Ni_2Cu_1Sn_4$ and $Ni_1Cu_2Sn_4$.

To understand the binding mechanism in the $(Ni,Cu)_3Sn_4$ crystal structure, electronic structures, such as density of states (DOS) and partial DOS (PDOS), were investigated. The DOS describes the number of states that are available to be occupied at a given energy level, while the PDOS measures the partial contributions from the component elements in the system. Figure 3 shows the total DOS of Ni₃Sn₄, and the PDOS of Ni and Sn atoms. It can be seen that the DOS at the energy range between 0 eV and -3 eV is governed by the Ni *d* state. When the energy is less than -5.5 eV, the Sn s state is the dominant part of the DOS, while the Sn p state becomes the dominant part of the DOS when the energy is larger than 0 eV. Furthermore, it is clear that hybridization between Ni d and Sn p at the energy range between -2 eV and -3 eV is the dominant factor of binding in Ni₃Sn₄, consistent with the study by Ghosh.¹

	Bulk Modulus	Shear Modulus	Young's Modulus	Poisson Ratio
	B (GPa)	G (GPa)	E (GPa)	v
${ m Ni}_3{ m Sn}_4$	VRH upper: 100.83	VRH upper: 53.51	VRH upper: 136.40	VRH upper: 0.27
$ m Ni_2Cu_1Sn_4$	VRH lower: 99.56	VRH 10wer: 49.75	VRH lower: 127.90	VRH lower: 0.29
	VRH upper: 88.9	VRH upper: 46.8	VRH upper: 119.44	VRH upper: 0.28
$ m Ni_1Cu_2Sn_4$	VRH lower: 87.5	VRH lower: 42.7	VRH lower: 110.18	VRH lower 0.29
	VRH upper: 83.6	VRH upper: 41.9	VRH upper: 107.71	VRH upper: 0.29
	VRH lower: 82.4	VRH lower: 39.1	VRH lower: 101.28	VRH lower: 0.30

Table III. Elastic properties of polycrystalline moduli calculated from single-crystal elastic constants



When Cu atoms substitute for Ni atoms in the Ni₃Sn₄ crystal structure, the DOS and PDOS profiles are altered significantly. A second peak appears near the Ni d state peak position, which may be mainly contributed by the Cu atom states, as shown in Fig. 4. The resulting PDOS of Ni, Cu, and Sn atoms in Ni₂Cu₁Sn₄ are illustrated in Fig. 5. It can be seen that hybridization between Ni d and Sn *p* states at the energy range -2.0 eV to -2.5 eVis still dominant in the binding in Ni₂Cu₁Sn₄. However, the amplitude of the Ni d state peak is significantly reduced due to the low Ni concentration in Ni₂Cu₁Sn₄, which also weakens the binding between Ni and Sn. The Cu atoms cannot accommodate the loss of the binding between Ni and Sn, as the Cu d state peak position exactly corresponds to the saddle-point position of $\operatorname{Sn} p$ at the energy level of about -3.5 eV. Overall, the binding energy in the $Ni_2Cu_1Sn_4$ crystal structure is expected to be weaker than that of Ni₃Sn₄, which is consistent with the heat of formation results, as well as the polycrystalline stiffness results.



Fig. 4. Total DOS comparison among $Ni_3Sn_4,\ Ni_2Cu_1Sn_4,\ and Ni_1Cu_2Sn_4.$

When the Cu solubility in $(Ni,Cu)_3Sn_4$ increases to 28.6 at.% (i.e., $Ni_1Cu_2Sn_4$), the amplitude of the Ni *d* state peak is further reduced, as shown in Fig. 6. In the meantime, the amplitude of the Sn *p* state at around -3.0 eV is also dramatically lowered. Similar to $Ni_2Cu_1Sn_4$, hybridization between Cu *d* and Sn *p* states is still not able to accommodate the loss of binding energy between Ni and Sn in $Ni_1Cu_2Sn_4$. Therefore, the binding energy in $Ni_1Cu_2Sn_4$ decreases as well, which is also in good agreement with the results on thermodynamic stability and elastic properties, as shown in Tables II and III.

To investigate the anisotropic elastic properties of Ni_3Sn_4 single crystal, an external normal strain of 10% was prescribed in different directions. According to Fig. 2a, c_{33} is the largest while c_{11} is the smallest in Ni_3Sn_4 . Thus a tensile strain of 10% was applied in the *x*- and *z*-directions, respectively. We have demonstrated that hybridization between Ni *d* and Sn *p* states is the dominant factor of binding in Ni_3Sn_4 . In addition, the Sn *p* state has nearly the same bandwidth as those of Ni *d* at the Fermi energy between 0 eV and -6 eV. Accordingly, the integrated total amount of Ni *d* state below the Fermi level was extracted to assess the change of the electronic states versus the applied strain. Figure 7 illustrates the integrated PDOS of Ni and







Sn atoms below the Fermi level after the normal strain was applied in the *x*- and *z*-directions. It was found that, in comparison with the undeformed structure, the total amount of the Ni *d* state decreased by 0.004 under an external strain $\varepsilon_{xx} = 0.1$, and by 0.021 under an external strain $\varepsilon_{zz} = 0.1$. In the meantime, the total amount of the Sn *p* state decreased by 0.160 under an external strain $\varepsilon_{xx} = 0.1$,



Fig. 7. Integrated PDOS of Ni states and Sn states under an external principle strain 0.1: (a) Ni d state change due to principle strain 0.1, and (b) Sn p state change due to principle strain 0.1.

and by 0.230 under an (forthcoming) external strain $\varepsilon_{zz} = 0.1$. Clearly, these results suggest that the changes of both Ni *d* and Sn *p* states versus ε_{zz} are larger than those versus ε_{xx} , revealing a larger stiffness against ε_{zz} than against ε_{xx} .

CONCLUSIONS

A first-principles approach was used to study the structure and elastic properties of $(Ni,Cu)_3Sn_4$ -based IMCs. The following conclusions are drawn:

- 1. The thermodynamic stability of $(Ni,Cu)_3Sn_4$ based IMCs was investigated by calculating the heat of formation. It was found that the thermodynamic stability decreases with increasing Cu concentration, with Ni_3Sn_4 being the most stable composition. This indicates that Cu solubility in the $(Ni,Cu)_3Sn_4$ crystal structure is less than 14.3 at.%, consistent with existing experimental results.
- 2. The polycrystalline elastic properties of $(Ni, Cu)_3Sn_4$ were extracted based on the calculated single-crystal elastic constants. The Ni_3Sn_4 phase shows larger moduli than those of Ni_2 -Cu₁Sn₄ and $Ni_1Cu_2Sn_4$. The electronic structure

calculation results show that hybridization of Ni d and Sn p states governs binding in Ni_3Sn_4 . The reduced moduli of Ni₂Cu₁Sn₄ and Ni₁Cu₂Sn₄ were attributed to decreased hybridization between Ni d and Sn p states.

3. The Ni_3Sn_4 phase exhibits anisotropic elastic properties. This is because the changes of the electronic states are different for strains applied in different directions. It is demonstrated that the changes of both Ni d and Sn p states in Ni₃Sn₄ are more pronounced for strain applied along the directions with larger stiffness.

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